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FIG. 1

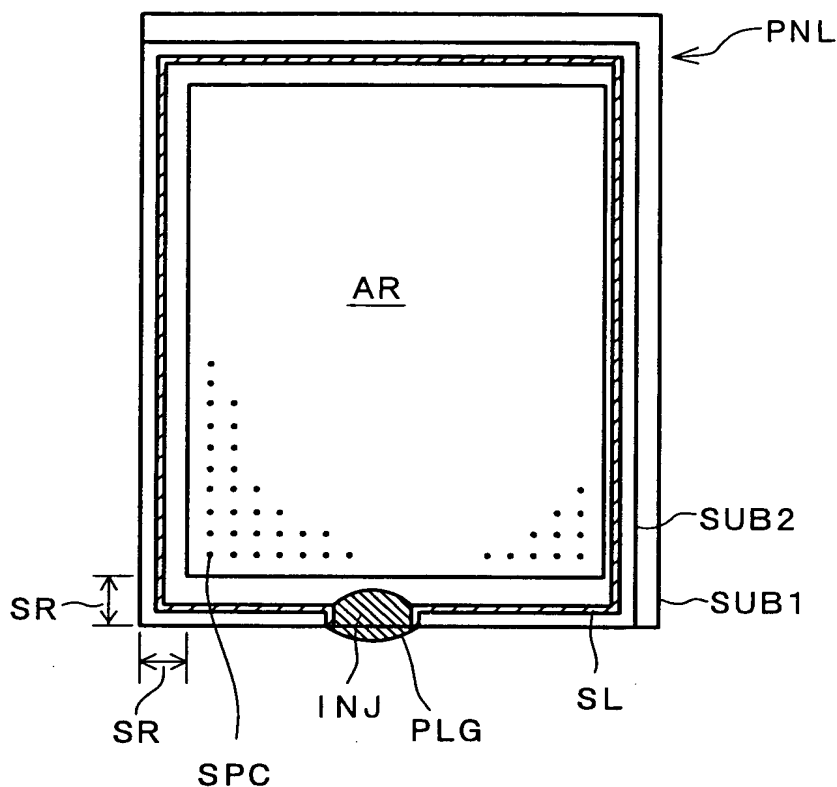
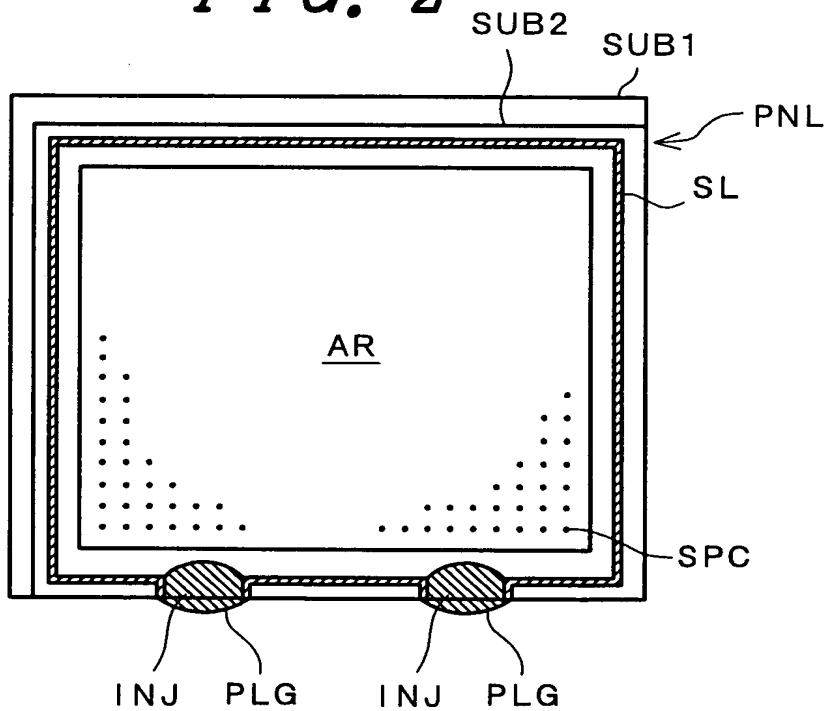


FIG. 2





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FIG. 3

MEASUREMENT CONDITIONS OF GC/MS

ANALYZER	M7200GC/MS
CONDITIONS OF GAS CHROMATOGRAPH (GC)	
COLUMN USED DB-5MS	0.25 mm ϕ x 30 m
CAPILLARY COLUMN SIZE	
CARRIER GAS HELIUM	
TEMPERATURE OF INJECTING PORT	260°C
COLUMN TEMPERATURE	FROM 100°C TO 280°C (TEMPERATURE INCREASE RATE: 5°C/MINUTE)
TRANSFER LINE TEMPERATURE	250°C
CONDITIONS OF GAS SPECTROMETER (MS)	
RANGE OF MASS NUMBER TO BE M/Z: 40-650 MEASURED	
ION SOURCE TEMPERATURE	230°C
IONIZING METHOD	ELECTRON IMPACT (EI) METHOD



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FIG. 4

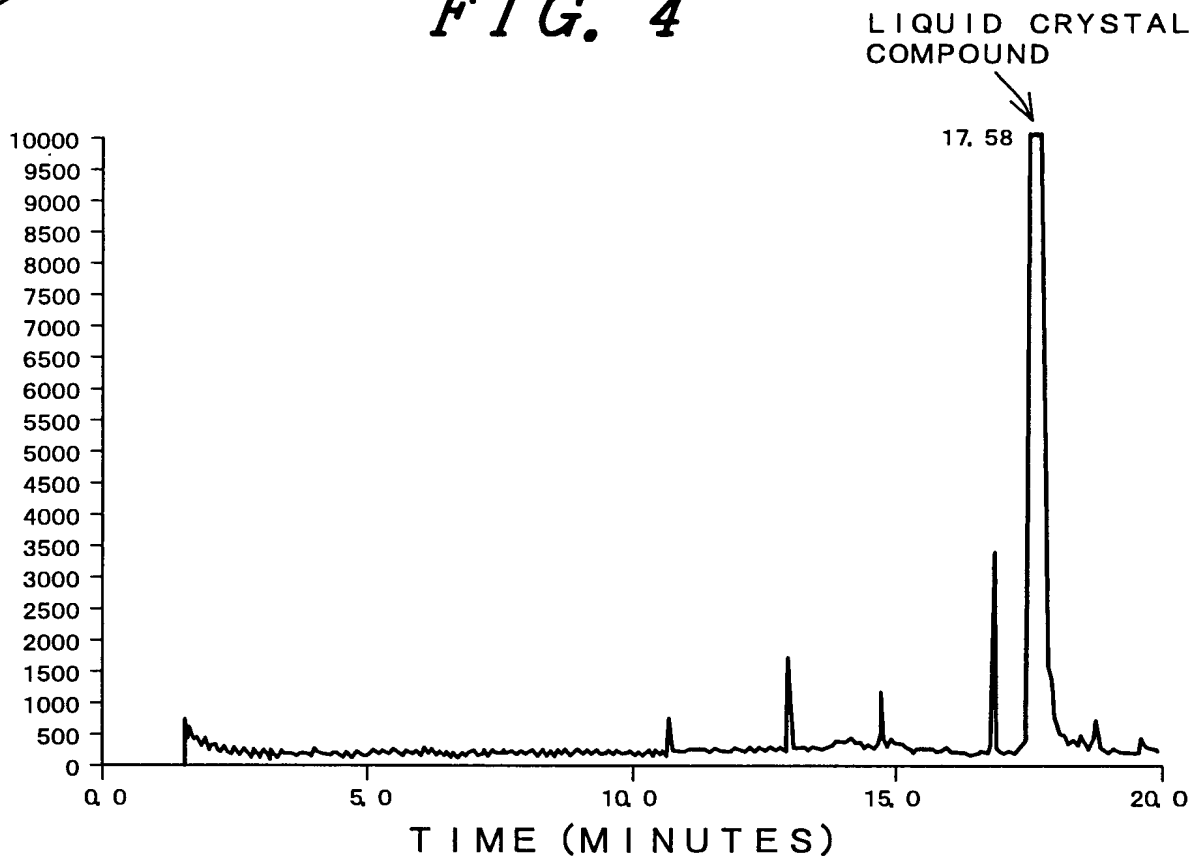
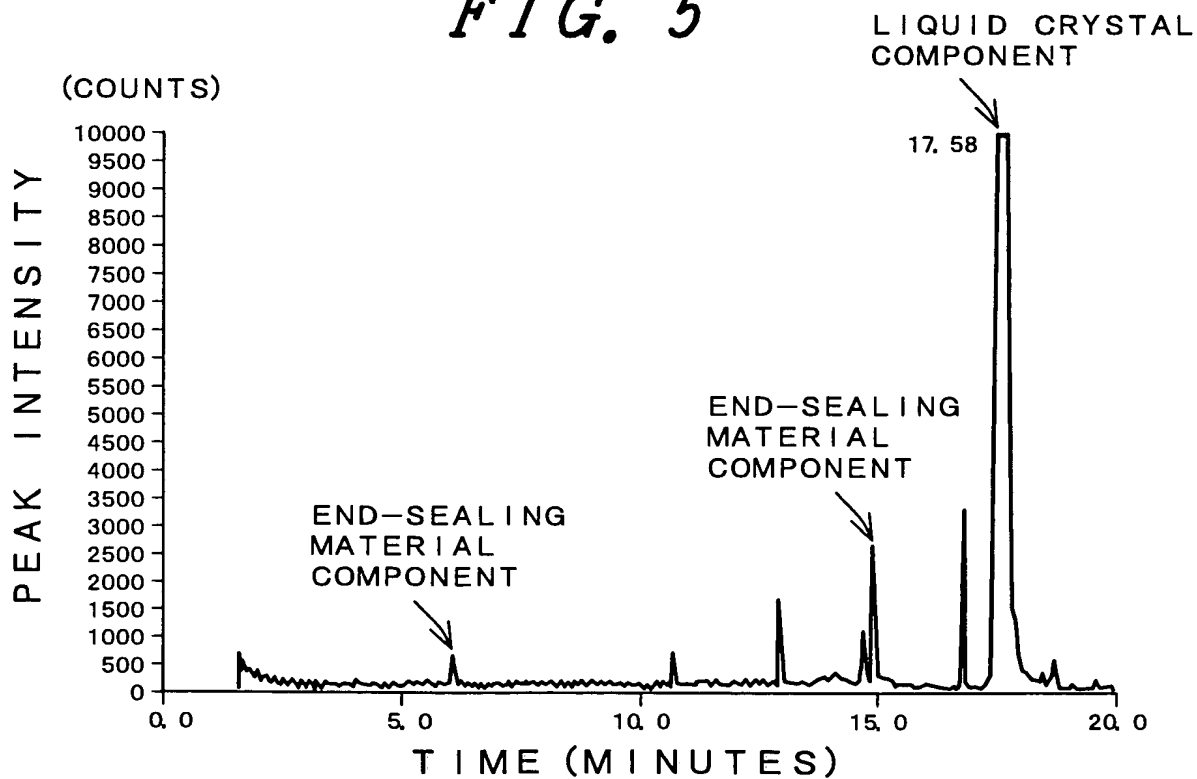


FIG. 5



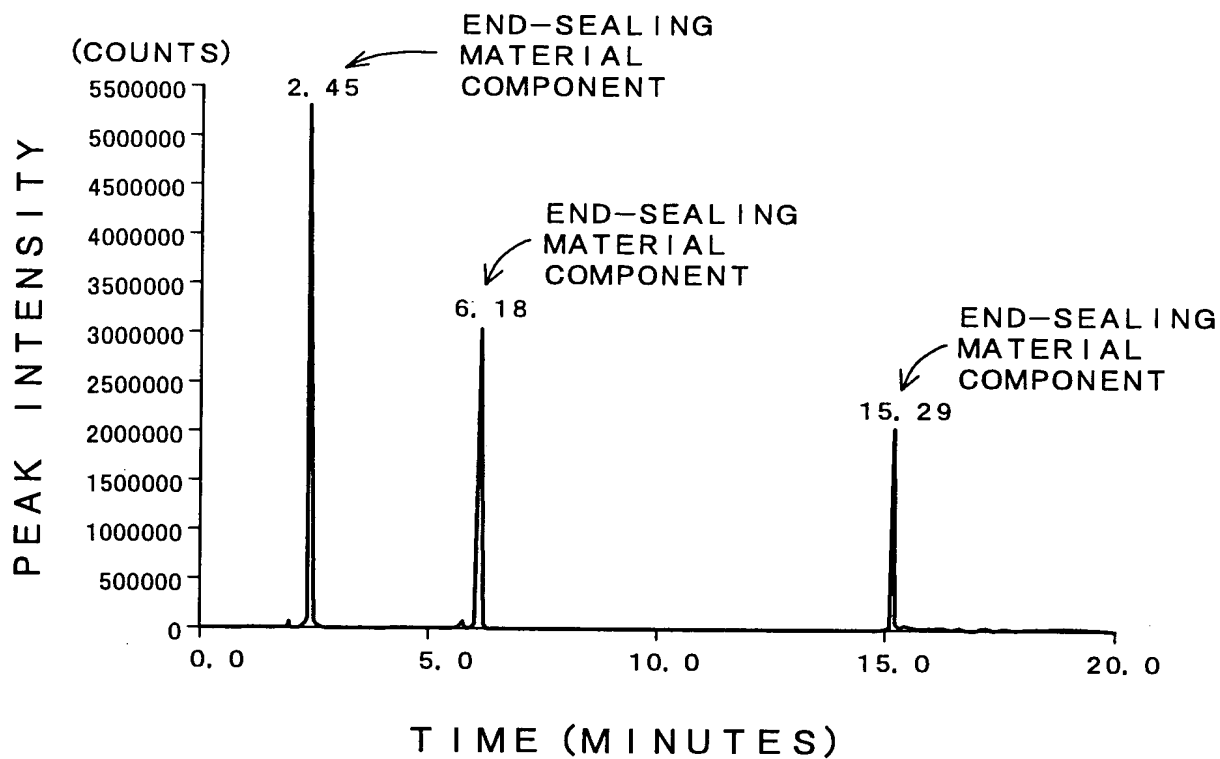


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FIG. 6





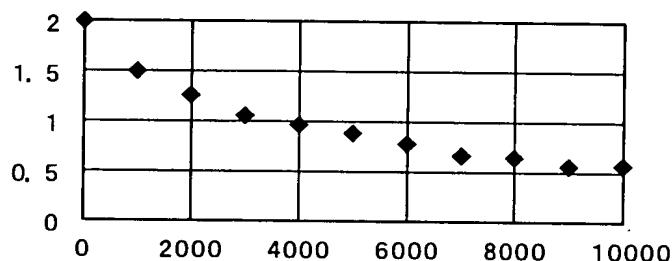
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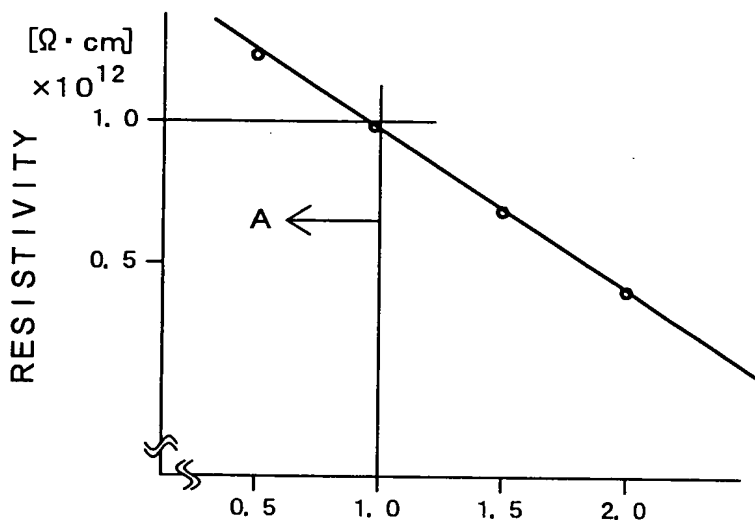
FIG. 7

AMOUNT OF CONSTITUTENT
COMPONENTS OF END-
SEALING MATERIAL WITH
RESPECT TO PEAK AREA
(10,000) OF LIQUID
CRYSTAL COMPOUND



ACCUMULATED ULTAVIOLET-
LIGHT AMOUNT (mJ/cm)

FIG. 8

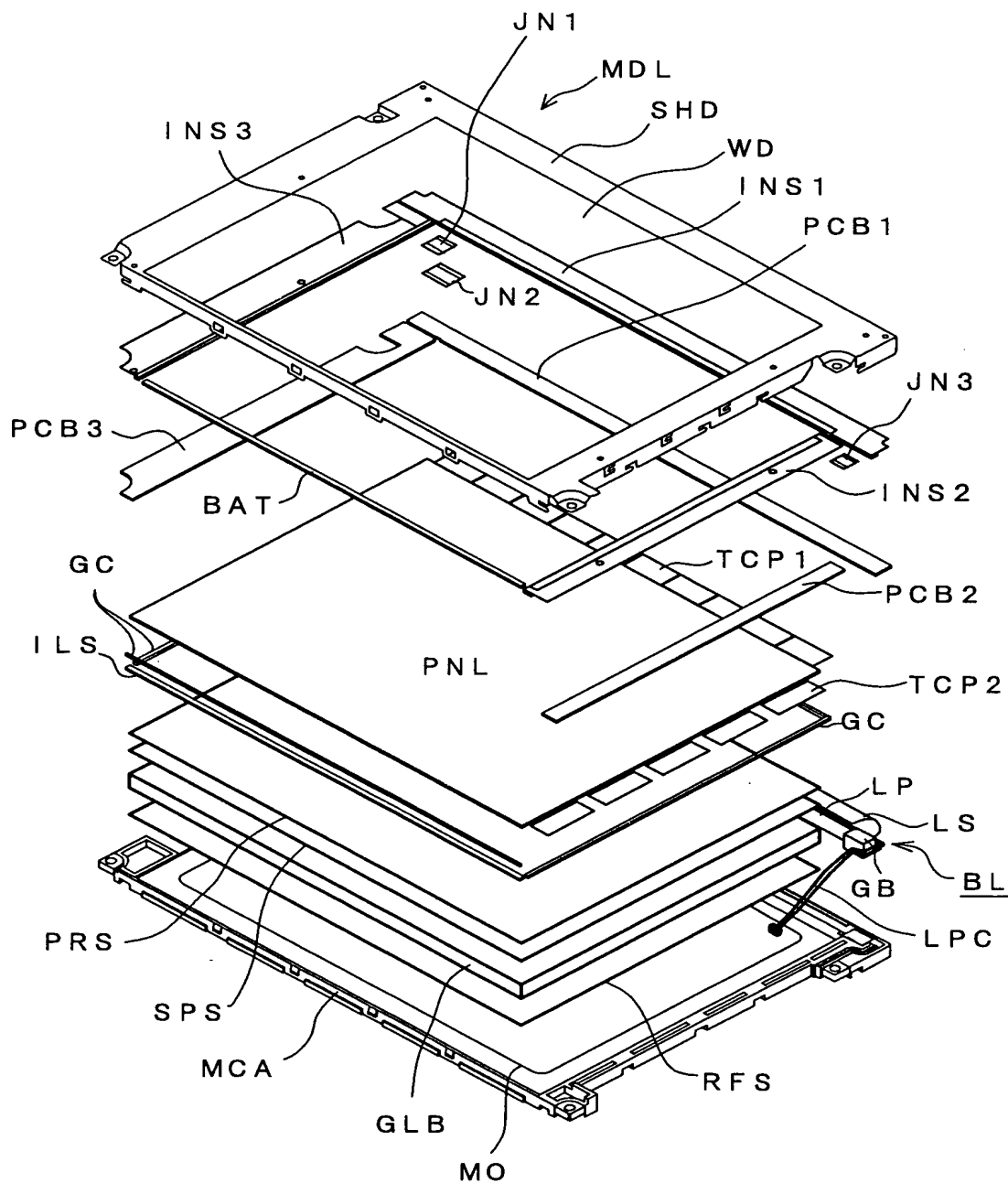


AMOUNT OF CONSTITUTENT
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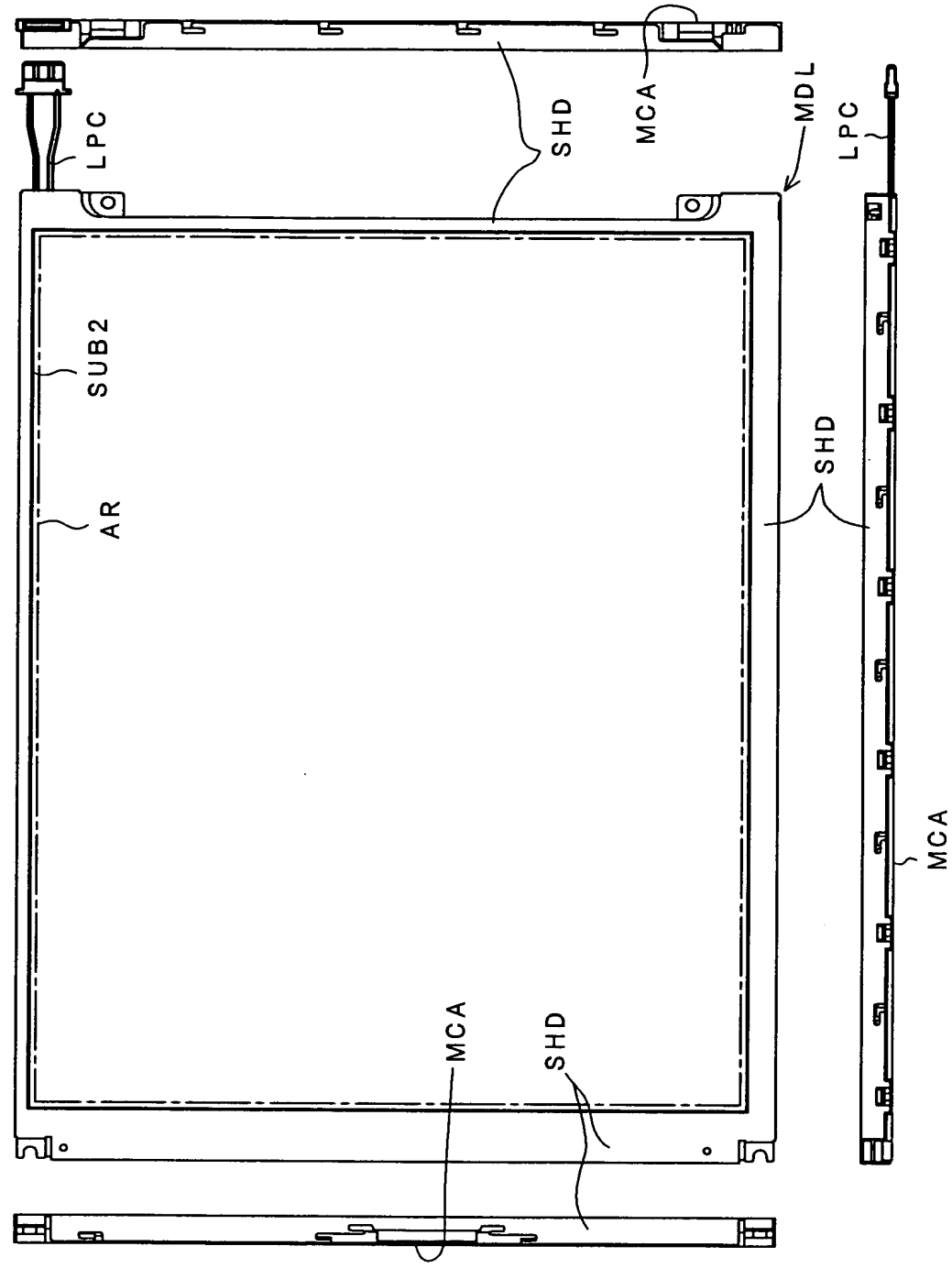
FIG. 9





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FIG. 10



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FIG. 11

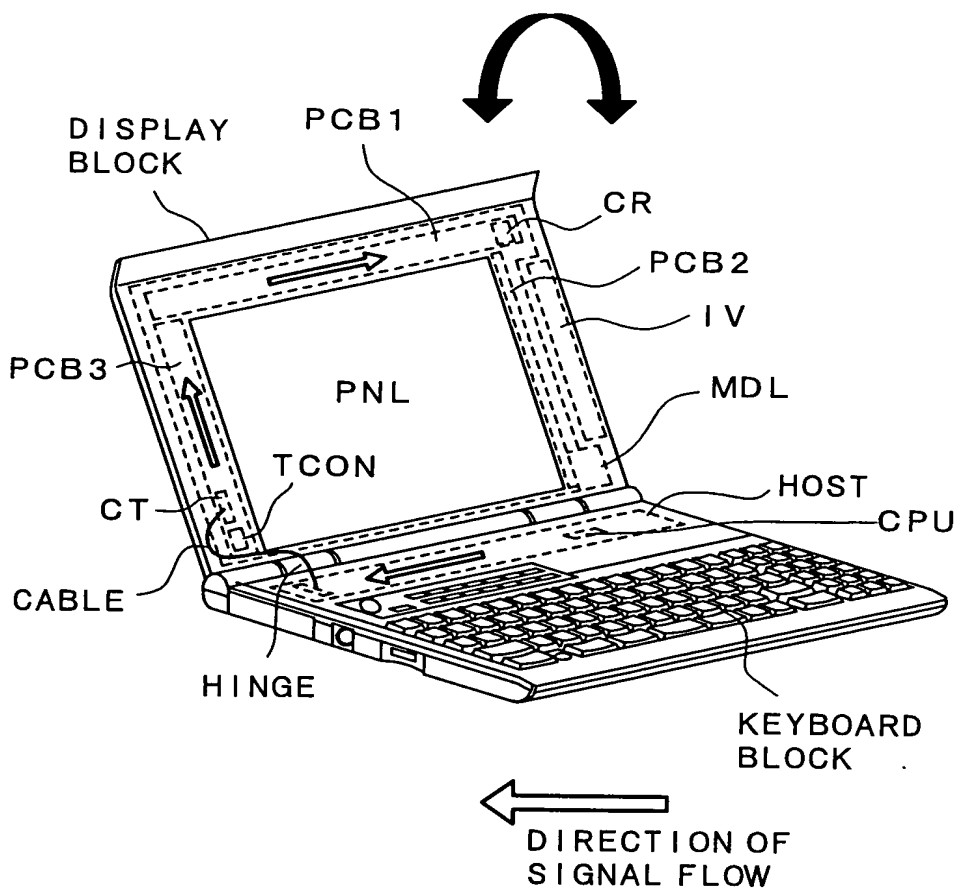
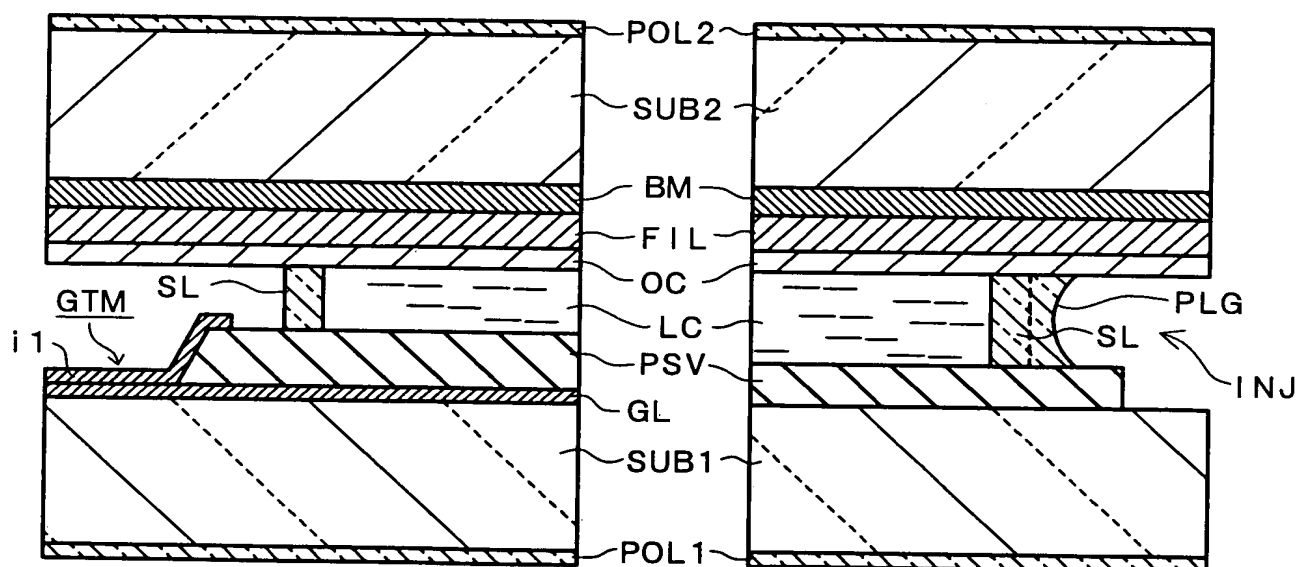


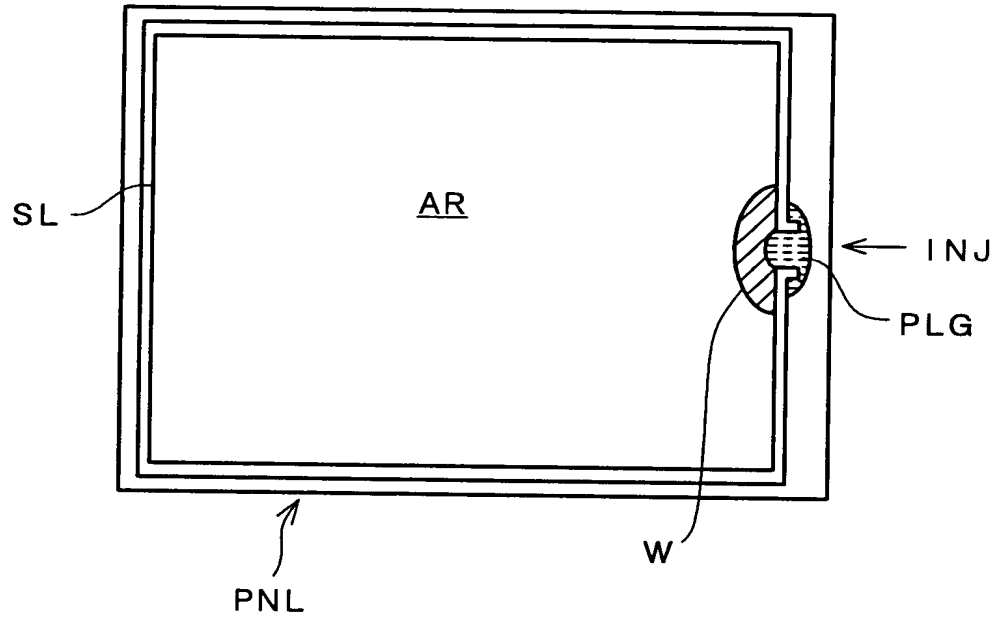
FIG. 12





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FIG. 13



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FIG. 14

